



JIANGSU CHANGJING ELECTRONICS TECHNOLOGY CO., LTD

CGWT80N65F2KAD

## CGWT80N65F2KAD

V <sub>CE</sub>	I <sub>C</sub> (T <sub>c</sub> =100°C)	V <sub>CE(sat)</sub>
650V	80A	1.7V

TO-247



### DESCRIPTION

The CGWT80N65F2KAD is used JSCJ's second generation IGBT technology, has advanced Trench and FS(Field Stop) Structure, it's with high application frequent, low Collector-Emitter Saturation Voltage and switching loss, can easy to use in parallel.

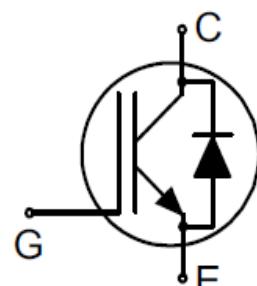
### Features

- 650V breakdown Voltage
- Low Vce(sat) and positive temperature coefficient
- High speed switching, Low switching loss
- With fast and soft recovery freewheeling diode
- Good EMI behavior

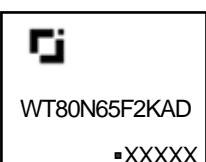
### Application

- UPS & FPC applications
- Solar Inverter
- EV Charger
- Power Storage
- Welder

### EQUIVALENT CIRCUIT



### MARKING



WT80N65F2KAD = Device code  
Solid dot = Green molding compound  
device, if none, the normal device  
XXXX = Code

Order Code	Package	Marking	Packing
CGWT80N65F2KAD	TO-247	WT80N65F2KAD	Tube

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### Absolute Maximum Ratings ( $T_c=25^\circ\text{C}$ unless otherwise noted)

Symbol	Parameter	Value	Units
$V_{CES}$	Collector-Emitter Voltage	650	V
$V_{GES}$	Gate-Emitter Voltage	$\pm 20$	V
	Gate-Emitter transient voltage	$\pm 30$	V
$I_c$	Collector Current <sup>(2)</sup>	100	A
	Collector Current @ $T_c=100^\circ\text{C}$	80	
$I_{Cpulse}$	Plused Collector Current, tp limited by $T_{Jmax}$	240	A
$I_{LM}^{(1)}$	Turn-off latching current	240	A
$I_F$	Continuous Diode Forward Current <sup>(2)</sup>	100	A
	Continuous Diode Forward Current @ $T_c=100^\circ\text{C}$	80	A
$I_{FM}$	Diode Pulsed Current, Limited by $T_{Jmax}$	240	A
$P_D$	Power Dissipation @ $T_c=25^\circ\text{C}$	390	W
	Power Dissipation @ $T_c = 100^\circ\text{C}$	156	
$T_J$	Operating junction temperature	-55 to 175	$^\circ\text{C}$
$T_{STG}$	Storage temperature	-55 to 150	$^\circ\text{C}$
$T_L$	Maximum lead temperature for soldering	260	$^\circ\text{C}$

(1)  $V_\infty = 400\text{V}$ ,  $V_{GE} = 15\text{ V}$ ,  $T_J \leq 150^\circ\text{C}$ .

(2) value limited by bondwire

### Thermal Characteristics

Symbol	Parameter	Value	Units
$R\theta_{JC}$	Maximum IGBT Junction-to-Case	0.32	$^\circ\text{C}/\text{W}$
$R\theta_{JC}$	Maximum Diode Junction-to-Case	0.6	$^\circ\text{C}/\text{W}$
$R\theta_{JA}$	Maximum Junction-to-Ambient	40	$^\circ\text{C}/\text{W}$

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## Electrical Characteristics (T<sub>J</sub>=25°C unless otherwise noted)

Symbol	Parameter	Test Conditions	Ration			Unit s
			Min.	Typ.	Max.	
<b>STATIC PARAMETERS</b>						
V <sub>(BR)CES</sub>	Collector-Emitter Breakdown Voltage	V <sub>GE</sub> =0V, I <sub>CE</sub> =1mA	650	--	--	V
I <sub>CES</sub>	Zero Gate Voltage Collector Current	V <sub>GE</sub> =0V, V <sub>CE</sub> =650V	--	--	1.0	mA
I <sub>GES</sub>	Gate-Emitter leakage current	V <sub>GE</sub> =±20V	--	--	±250	nA
		V <sub>GE</sub> =±30V	--	--	±500	nA
V <sub>GE(th)</sub>	Gate-Emitter Threshold Voltage	I <sub>C</sub> =1mA, V <sub>CE</sub> =V <sub>GE</sub>	4		6.5	V
V <sub>F</sub>	Diode Forward Voltage	I <sub>F</sub> =80A, T <sub>c</sub> =25°C		1.52		V
		I <sub>F</sub> =80A, T <sub>c</sub> =125°C		1.27		V
		I <sub>F</sub> =80A, T <sub>c</sub> =150°C		1.22		V
V <sub>CE(sat)</sub>	Collector-Emitter Saturation Voltage	I <sub>C</sub> =80A, V <sub>GE</sub> =15V, T <sub>J</sub> =25°C		1.7		V
		I <sub>C</sub> =80A, V <sub>GE</sub> =15V, T <sub>J</sub> =125°C		2		V
		I <sub>C</sub> =80A, V <sub>GE</sub> =15V, T <sub>J</sub> =150°C		2.15		V
<b>DYNAMIC PARAMETERS</b>						
C <sub>ies</sub>	Input Capacitance	V <sub>CE</sub> =30V, V <sub>GE</sub> =0V f=1MHz	--	2602	--	pF
C <sub>oes</sub>	Output Capacitance		--	256	--	
C <sub>res</sub>	Reverse Transfer Capacitance		--	30	--	
R <sub>g</sub>	Gate resistance	V <sub>GE</sub> =0V, CE short, f=1MHz	--	0.66	--	Ω
<b>SWITCHING PARAMETERS</b>						
t <sub>d(on)</sub>	Turn-On Delay Time	V <sub>CE</sub> =400V, I <sub>C</sub> =80A, R <sub>g</sub> =10Ω, V <sub>GE</sub> =15V, Inductive Load T <sub>J</sub> =25°C	--	26	--	ns
t <sub>r</sub>	Current Rise Time		--	68	--	
t <sub>d(off)</sub>	Turn-Off Delay Time		--	94	--	
t <sub>f</sub>	Current Fall Time		--	26	--	
E <sub>on</sub> <sup>(3)</sup>	Turn-On Switching Energy		--	2.69	--	mJ
E <sub>off</sub>	Turn-Off Switching Energy		--	0.87	--	
E <sub>ts</sub>	Total Switching Energy		--	3.56	--	
Q <sub>G</sub>	Total Gate Charge	V <sub>CE</sub> = 480 V, I <sub>C</sub> = 80 A, V <sub>GE</sub> = 15 V		108.8		nC
Q <sub>GE</sub>	Gate to Emitter Charge			27.2		nC
Q <sub>GC</sub>	Gate to Collector Charge			58.8		nC
t <sub>rr</sub>	Diode reverse recovery time	VR = 400V, IF = 80A, dI/dt = 100A/μs		90		nS
Q <sub>rr</sub>	Diode reverse recovery charge			352		nC
I <sub>rm</sub>	Diode peak reverse recovery current			7		A

(3) Including the reverse recovery of the diode.

## TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS

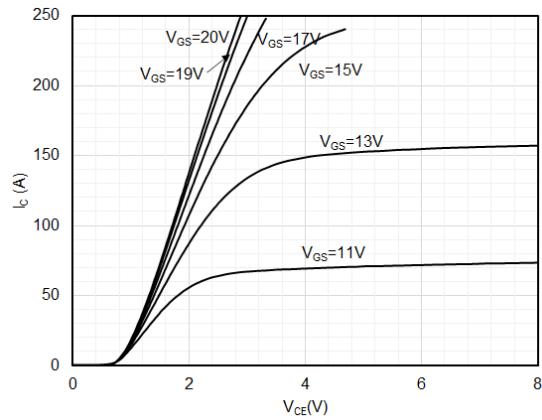


Figure 1: Output Characteristic  
( $T_j=25^\circ\text{C}$ )

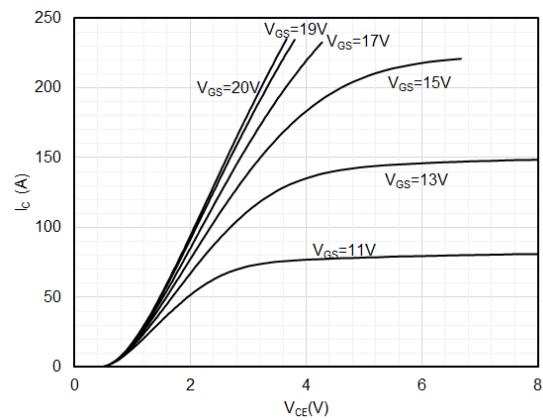


Figure 2: Output Characteristic  
( $T_j=125^\circ\text{C}$ )

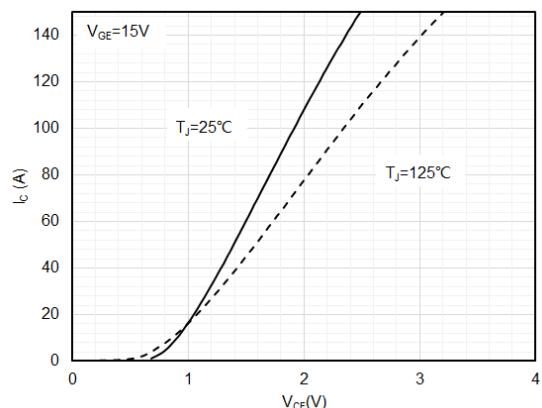


Figure 3: Collector-Emitter Saturation Voltage

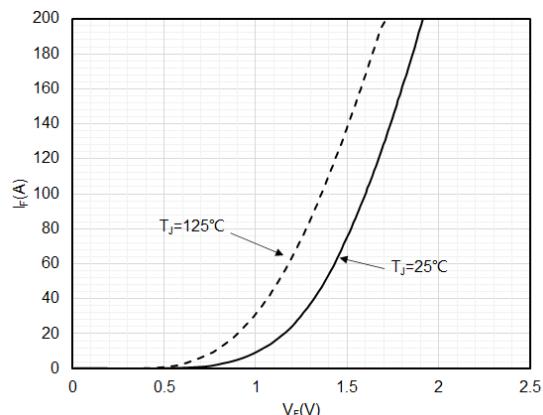


Figure 4: Diode Characteristic

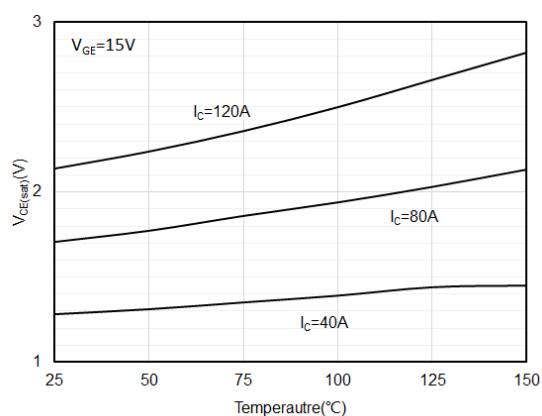


Figure 5: Collector-Emitter Saturation Voltage vs.  
Junction Temperature

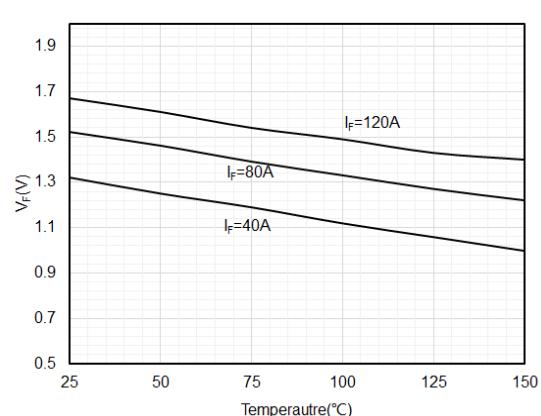


Figure 6: Diode Forward voltage vs. Junction  
Temperature

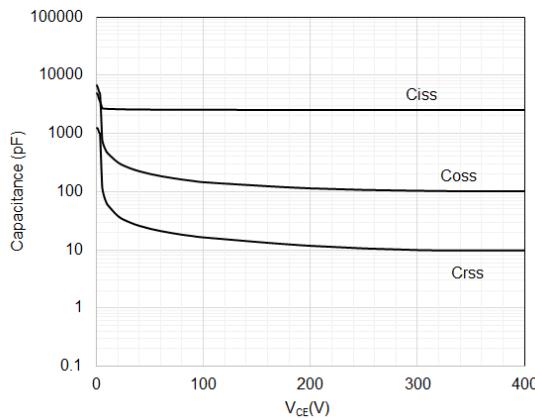


Figure 7: Capacitance Characteristic

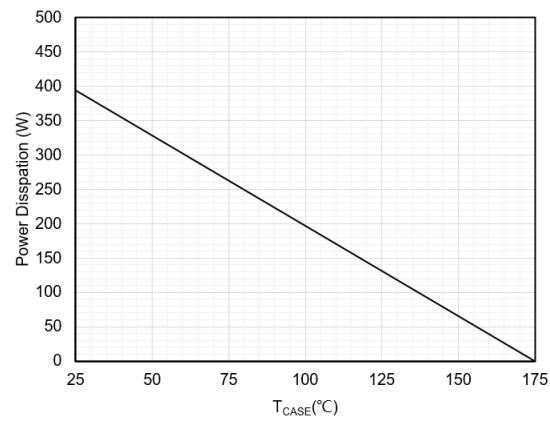


Figure 8: Power Dissipation as a Function of Case

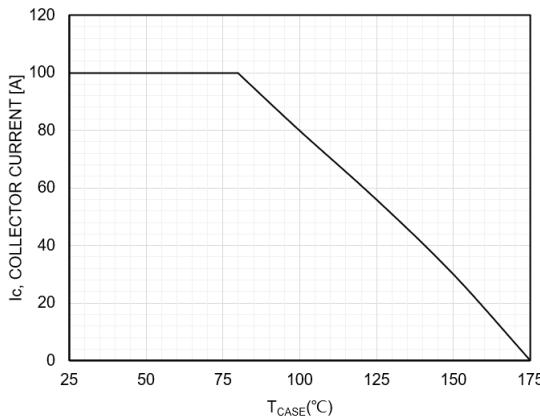


Figure 9: Collector Current as a Function of Case

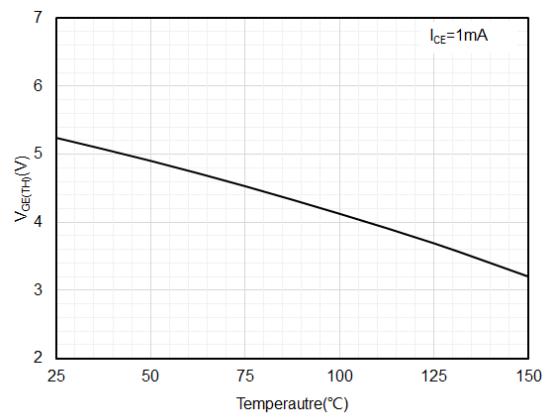


Figure 10:  $V_{GE(TH)}$  vs.  $T_J$

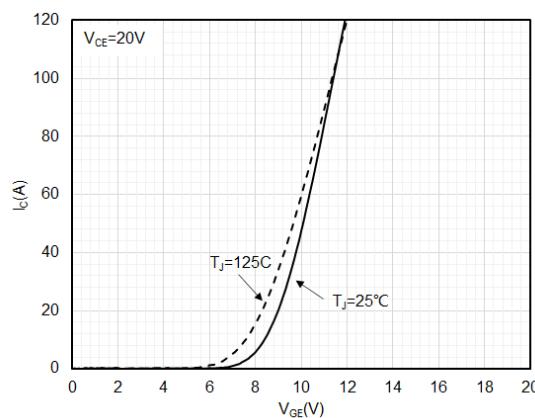


Figure 11: Transfer Characteristic

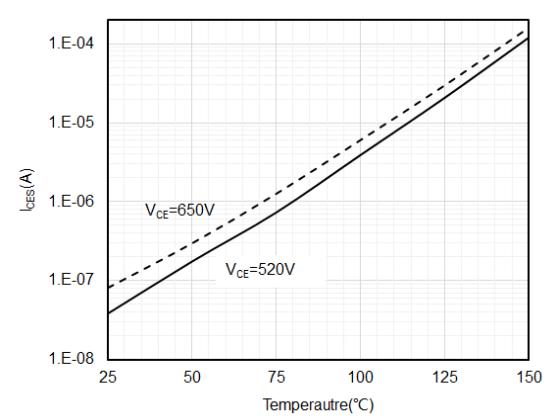


Figure 12: Reverse Leakage Current vs.  $T_J$

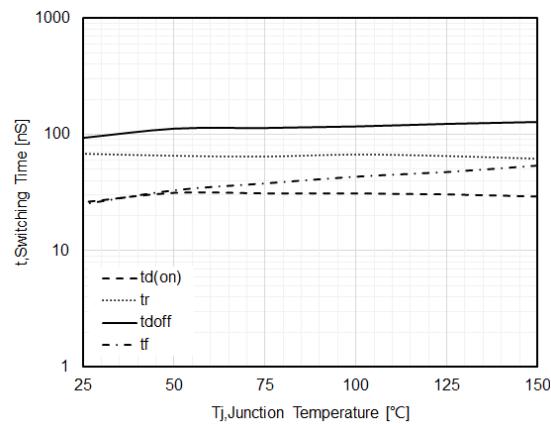


Figure 13 Typical switching times as a function of junction temperature

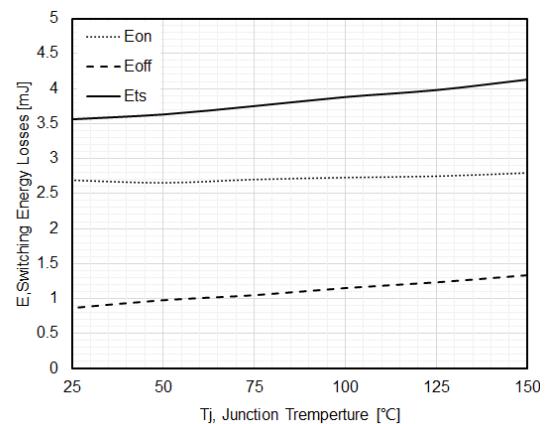
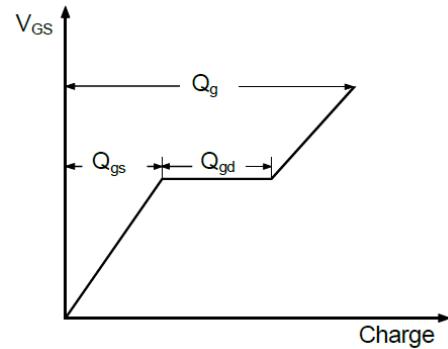
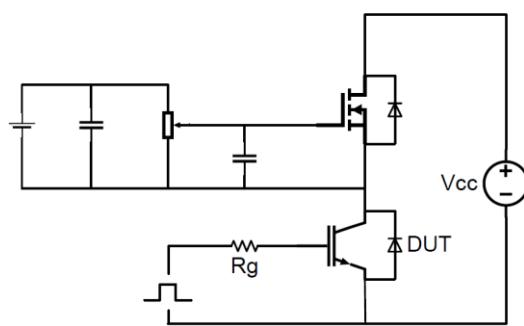


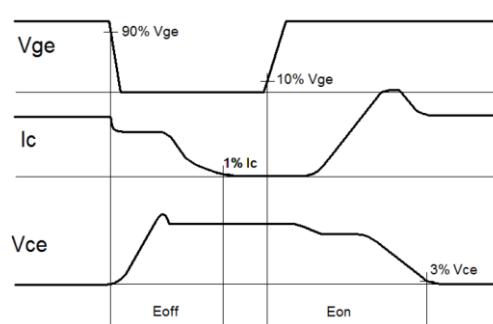
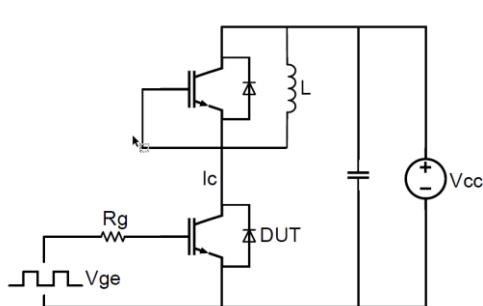
Figure 14 Typical switching energy losses as a function of junction temperature

## TEST CIRCUIT AND WAVEFORMS

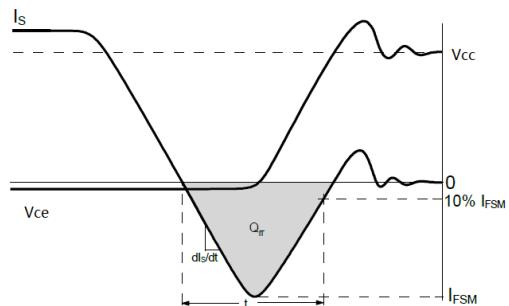
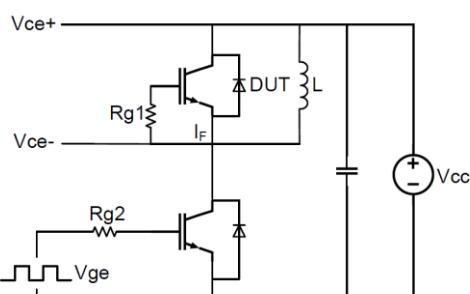
### Gate Charge



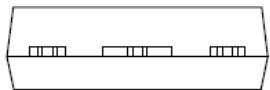
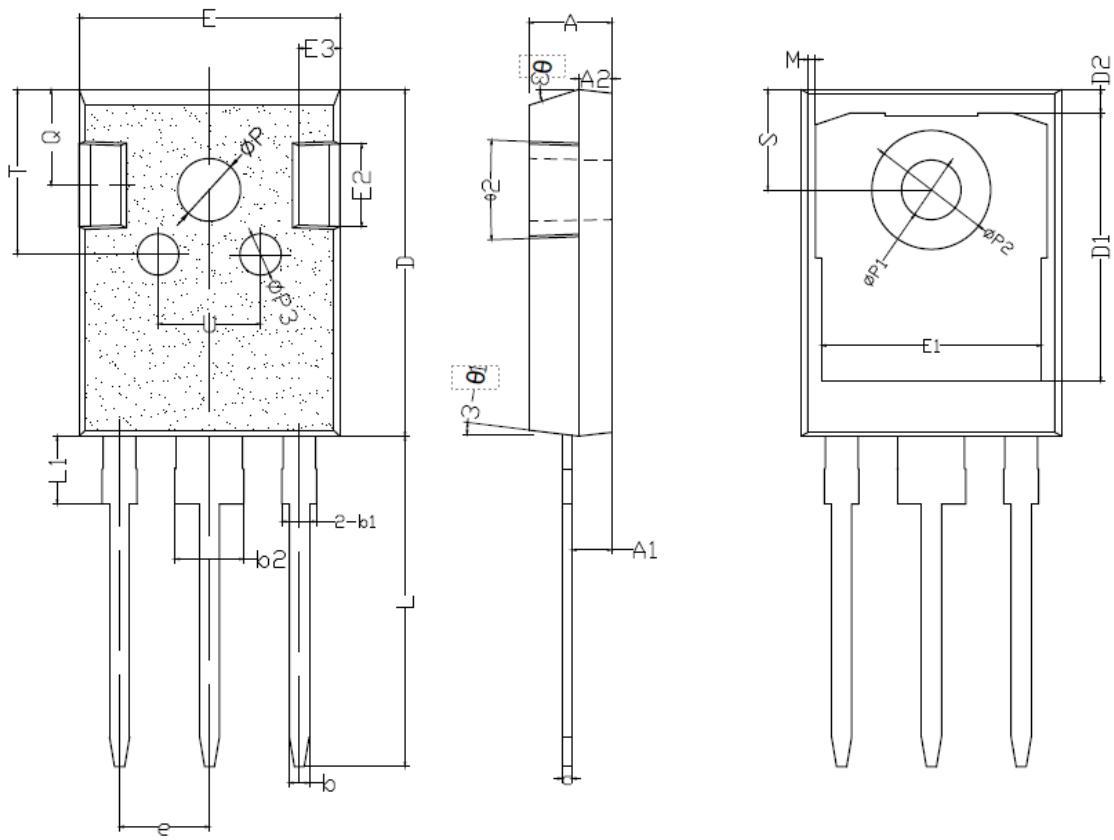
### Inductive Switching Test Circuit



### Diode Reverse Recovery



**TO-247 PACKAGE OUTLINE DIMENSIONS**



SYMBOL	mm		
	MIN	NOM	MAX
*A	4.90	5.00	5.10
*A1	2.31	2.41	2.51
A2	1.90	2.00	2.10
*b	1.15	1.20	1.25
*b1	1.95	2.10	2.25
*b2	2.95	3.10	3.25
*c	0.55	0.60	0.65
*D	20.90	21.00	21.10
D1	16.35	16.55	16.75
D2	1.05	1.20	1.35
*E	15.70	15.80	15.90

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E1	13.10	13.25	13.40
E2	4.85	4.95	5.10
E3	2.40	2.50	2.60
*e	5.40	5.44	5.48
*L	19.80	19.98	20.15
*L1	-	-	4.30
*ΦP	3.40	3.50	3.60
*ΦP1	6.90	7.10	7.30
ΦP2	2.40	2.50	2.60
ΦP3	2.40	2.50	2.60
Q	5.60	5.80	6.00
*S	6.05	6.15	6.25
T	9.80	10.00	10.20
U	6.00	6.20	6.40
θ1	5°	7°	9°
θ2	1°	3°	5°
θ3	13°	15°	17°
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[FGY75T120SWD](#) [EL3120S1\(TA\)\(SAS\)-V](#) [IHW15N120E1](#) [IKQ75N120CS6](#) [IKW50N65WR5](#) [SL15T65FK](#) [KGF50N65KDF-U/H](#)  
[IHFW40N65R5S](#) [IKW08N120CS7XKSA1](#) [IKQ75N120CH3](#) [IHW30N160R5](#) [SGM100HF12A1TFD](#) [CRG50T60AK3SD](#) [CRG40T60AN3S](#)